

# 74HC373D

## 1. Functional Description

- Octal D-Type Latch with 3-State Outputs

## 2. General

The 74HC373D is a high speed CMOS OCTAL LATCH with 3-STATE OUTPUT fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

These 8-bit D-type latches are controlled by a latch enable input (LE) and an output enable input ( $\overline{OE}$ ).

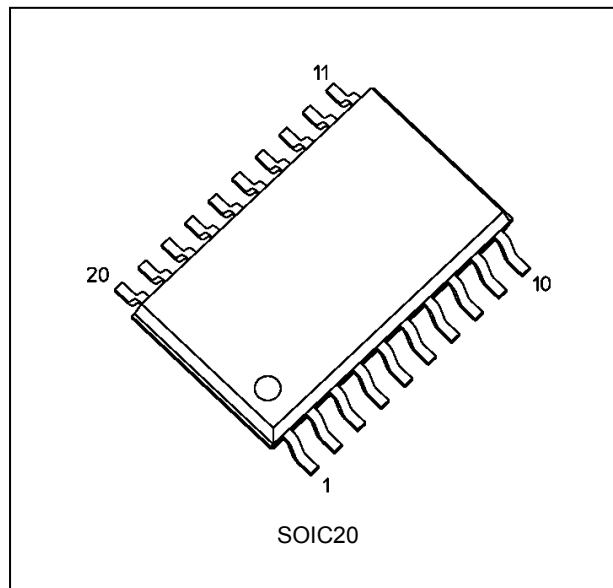
When the  $\overline{OE}$  input is high, the eight outputs are in a high impedance state.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

## 3. Features

- (1) High speed:  $t_{pd} = 12$  ns (typ.) at  $V_{CC} = 6.0$  V
- (2) Low power dissipation:  $I_{CC} = 4.0$   $\mu$ A (max) at  $T_a = 25$  °C
- (3) Balanced propagation delays:  $t_{PLH} \approx t_{PHL}$
- (4) Wide operating voltage range:  $V_{CC(opr)} = 2.0$  V to 6.0 V

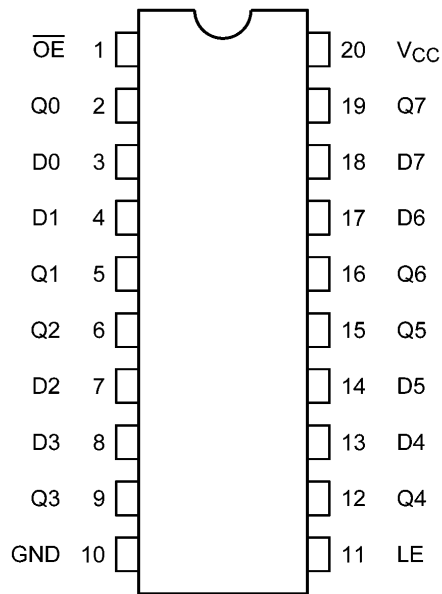
## 4. Packaging



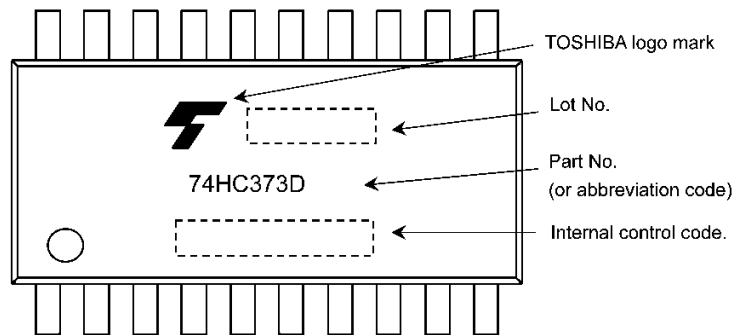
Start of commercial production

2016-03

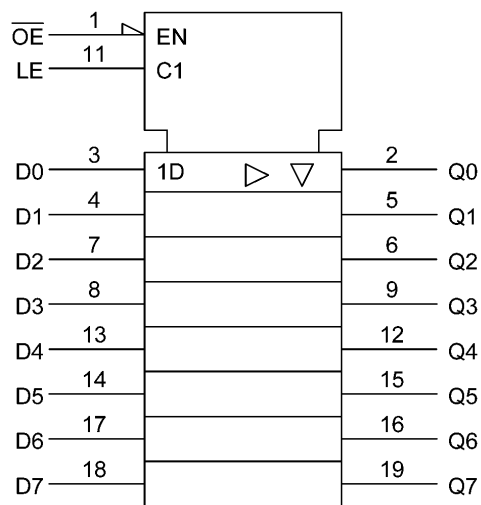
**5. Pin Assignment**



**6. Marking**



**7. IEC Logic Symbol**

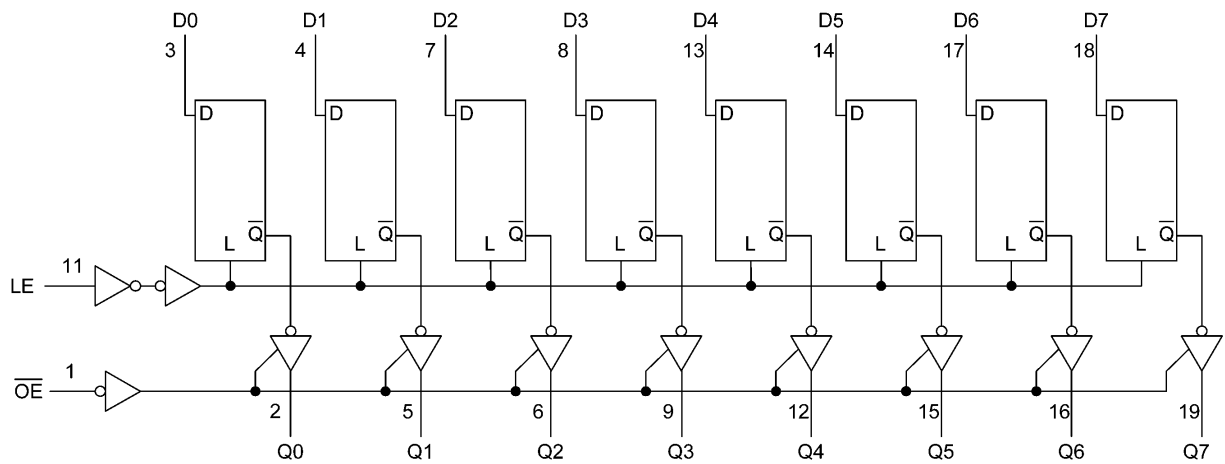


**8. Truth Table**

INPUT $\overline{OE}$	INPUT LE	INPUT D	OUTPUT Q
H	X	X	Z
L	L	X	Qn
L	H	L	L
L	H	H	H

X: Don't Care  
 Z: High Impedance  
 Qn: Q outputs are latched at the time when the LE input is taken to low logic level.

**9. System Diagram**



## 10. Absolute Maximum Ratings (Note)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	$V_{CC}$		-0.5 to 7.0	V
Input voltage	$V_{IN}$		-0.5 to $V_{CC} + 0.5$	V
Output voltage	$V_{OUT}$		-0.5 to $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$		$\pm 20$	mA
Output diode current	$I_{OK}$		$\pm 20$	mA
Output current	$I_{OUT}$		$\pm 35$	mA
$V_{CC}$ /ground current	$I_{CC}$		$\pm 75$	mA
Power dissipation	$P_D$	(Note 1)	500	mW
Storage temperature	$T_{stg}$		-65 to 150	$^{\circ}\text{C}$

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1:  $P_D$  derates linearly with -8 mW/ $^{\circ}\text{C}$  above 85 $^{\circ}\text{C}$

## 11. Operating Ranges (Note)

Characteristics	Symbol	Test Condition	Rating	Unit
Supply voltage	$V_{CC}$	—	2.0 to 6.0	V
Input voltage	$V_{IN}$	—	0 to 5.5	V
Output voltage	$V_{OUT}$	—	0 to $V_{CC}$	V
Operating temperature	$T_{opr}$	—	-40 to 125	$^{\circ}\text{C}$
Input rise and fall times	$t_r, t_f$	—	0 to 50	$\mu\text{s}$

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either  $V_{CC}$  or GND.

**12. Electrical Characteristics**

**12.1. DC Characteristics (Unless otherwise specified,  $T_a = 25\text{ }^\circ\text{C}$ )**

Characteristics	Symbol	Test Condition	$V_{CC}$ (V)	Min	Typ.	Max	Unit	
High-level input voltage	$V_{IH}$	—	2.0	1.50	—	—	V	
			4.5	3.15	—	—	V	
			6.0	4.20	—	—	V	
Low-level input voltage	$V_{IL}$	—	2.0	—	—	0.50	V	
			4.5	—	—	1.35	V	
			6.0	—	—	1.80	V	
High-level output voltage	$V_{OH}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OH} = -20\text{ }\mu\text{A}$	2.0	1.9	2.0	—	V
				4.5	4.4	4.5	—	
				6.0	5.9	6.0	—	
			$I_{OH} = -6\text{ mA}$	4.5	4.18	4.31	—	
				$I_{OH} = -7.8\text{ mA}$	6.0	5.68	5.80	—
Low-level output voltage	$V_{OL}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OL} = 20\text{ }\mu\text{A}$	2.0	—	0.0	0.1	V
				4.5	—	0.0	0.1	
				6.0	—	0.0	0.1	
			$I_{OL} = 6\text{ mA}$	4.5	—	0.17	0.26	
				$I_{OL} = 7.8\text{ mA}$	6.0	—	0.18	0.26
3-state output OFF-state leakage current	$I_{OZ}$	$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND	6.0	—	—	$\pm 0.5$	$\mu\text{A}$	
Input leakage current	$I_{IN}$	$V_{IN} = V_{CC}$ or GND	6.0	—	—	$\pm 0.1$	$\mu\text{A}$	
Quiescent supply current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND $I_O = 0\text{ A}$	6.0	—	—	4.0	$\mu\text{A}$	

**12.2. DC Characteristics (Unless otherwise specified,  $T_a = -40$  to  $85\text{ }^\circ\text{C}$ )**

Characteristics	Symbol	Test Condition	$V_{CC}$ (V)	Min	Max	Unit	
High-level input voltage	$V_{IH}$	—	2.0	1.50	—	V	
			4.5	3.15	—		
			6.0	4.20	—		
Low-level input voltage	$V_{IL}$	—	2.0	—	0.50	V	
			4.5	—	1.35		
			6.0	—	1.80		
High-level output voltage	$V_{OH}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OH} = -20\text{ }\mu\text{A}$	2.0	1.9	—	V
				4.5	4.4	—	
				6.0	5.9	—	
			$I_{OH} = -6\text{ mA}$	4.5	4.13	—	
				$I_{OH} = -7.8\text{ mA}$	6.0	5.63	—
Low-level output voltage	$V_{OL}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OL} = 20\text{ }\mu\text{A}$	2.0	—	0.1	V
				4.5	—	0.1	
				6.0	—	0.1	
			$I_{OL} = 6\text{ mA}$	4.5	—	0.33	
				$I_{OL} = 7.8\text{ mA}$	6.0	—	0.33
3-state output OFF-state leakage current	$I_{OZ}$	$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND	6.0	—	$\pm 5.0$	$\mu\text{A}$	
Input leakage current	$I_{IN}$	$V_{IN} = V_{CC}$ or GND	6.0	—	$\pm 1.0$	$\mu\text{A}$	
Quiescent supply current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND $I_O = 0\text{ A}$	6.0	—	40.0	$\mu\text{A}$	

**12.3. DC Characteristics (Unless otherwise specified,  $T_a = -40$  to  $125$  °C)**

Characteristics	Symbol	Test Condition	$V_{CC}$ (V)	Min	Max	Unit	
High-level input voltage	$V_{IH}$	—	2.0	1.50	—	V	
			4.5	3.15	—		
			6.0	4.20	—	V	
Low-level input voltage	$V_{IL}$	—	2.0	—	0.50	V	
			4.5	—	1.35		
			6.0	—	1.80	V	
High-level output voltage	$V_{OH}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OH} = -20 \mu A$	2.0	1.9	—	V
				4.5	4.4	—	
				6.0	5.9	—	
			$I_{OH} = -6$ mA	4.5	3.7	—	
			$I_{OH} = -7.8$ mA	6.0	5.2	—	
Low-level output voltage	$V_{OL}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OL} = 20 \mu A$	2.0	—	0.1	V
				4.5	—	0.1	
				6.0	—	0.1	
			$I_{OL} = 6$ mA	4.5	—	0.4	
			$I_{OL} = 7.8$ mA	6.0	—	0.4	V
3-state output OFF-state leakage current	$I_{OZ}$	$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND	6.0	—	$\pm 10.0$	$\mu A$	
Input leakage current	$I_{IN}$	$V_{IN} = V_{CC}$ or GND	6.0	—	$\pm 1.0$	$\mu A$	
Quiescent supply current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND $I_O = 0$ A	6.0	—	160.0	$\mu A$	

**12.4. Timing Requirements (Unless otherwise specified,  $T_a = 25\text{ }^\circ\text{C}$ , Input:  $t_r = t_f = 6\text{ ns}$ )**

Characteristics	Symbol	Test Condition	$V_{CC}$ (V)	Limit	Unit
Minimum pulse width (LE)	$t_{w(H)}$	—	2.0	75	ns
			4.5	15	
			6.0	13	
Minimum setup time (Dn)	$t_s$	—	2.0	50	ns
			4.5	10	
			6.0	9	
Minimum hold time (Dn)	$t_h$	—	2.0	5	ns
			4.5	5	
			6.0	5	

**12.5. Timing Requirements (Unless otherwise specified,  $T_a = -40\text{ to }85\text{ }^\circ\text{C}$ , Input:  $t_r = t_f = 6\text{ ns}$ )**

Characteristics	Symbol	Test Condition	$V_{CC}$ (V)	Limit	Unit
Minimum pulse width (LE)	$t_{w(H)}$	—	2.0	95	ns
			4.5	19	
			6.0	16	
Minimum setup time (Dn)	$t_s$	—	2.0	65	ns
			4.5	13	
			6.0	11	
Minimum hold time (Dn)	$t_h$	—	2.0	5	ns
			4.5	5	
			6.0	5	

**12.6. Timing Requirements (Unless otherwise specified,  $T_a = -40\text{ to }125\text{ }^\circ\text{C}$ , Input:  $t_r = t_f = 6\text{ ns}$ )**

Characteristics	Symbol	Test Condition	$V_{CC}$ (V)	Limit	Unit
Minimum pulse width (LE)	$t_{w(H)}$	—	2.0	120	ns
			4.5	24	
			6.0	20	
Minimum setup time (Dn)	$t_s$	—	2.0	75	ns
			4.5	15	
			6.0	13	
Minimum hold time (Dn)	$t_h$	—	2.0	5	ns
			4.5	5	
			6.0	5	

**12.7. AC Characteristics (Unless otherwise specified,  $T_a = 25\text{ }^\circ\text{C}$ , Input:  $t_r = t_f = 6\text{ ns}$ )**

Characteristics	Symbol	Note	Test Condition	$V_{CC}$ (V)	$C_L$ (pF)	Min	Typ.	Max	Unit
Output transition time	$t_{TLH}, t_{THL}$		—	2.0	50	—	20	60	ns
				4.5		—	6	12	
				6.0		—	5	10	
Propagation delay time (LE-Q)	$t_{PLH}, t_{PHL}$		—	2.0	50	—	42	125	ns
				4.5		—	14	25	
				6.0		—	12	21	
				2.0	150	—	57	175	ns
				4.5		—	19	35	
				6.0		—	16	30	
Propagation delay time (D-Q)	$t_{PLH}, t_{PHL}$		—	2.0	50	—	42	125	ns
				4.5		—	14	25	
				6.0		—	12	21	
				2.0	150	—	57	175	ns
				4.5		—	19	35	
				6.0		—	16	30	
Output enable time	$t_{PZL}, t_{PZH}$		$R_L = 1\text{ k}\Omega$	2.0	50	—	39	125	ns
				4.5		—	13	25	
				6.0		—	11	21	
				2.0	150	—	54	175	ns
				4.5		—	18	35	
				6.0		—	15	30	
Output disable time	$t_{PLZ}, t_{PHZ}$		$R_L = 1\text{ k}\Omega$	2.0	50	—	30	125	ns
				4.5		—	14	25	
				6.0		—	13	21	
Input capacitance	$C_{IN}$		—			—	3	—	pF
Output capacitance	$C_{OUT}$		—			—	4	—	pF
Power dissipation capacitance	$C_{PD}$	(Note 1)	—			—	11	—	pF

Note 1:  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation.

$$I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/8 \text{ (per latch)}$$



**12.8. AC Characteristics**

(Unless otherwise specified,  $T_a = -40$  to  $85$  °C, Input:  $t_r = t_f = 6$  ns)

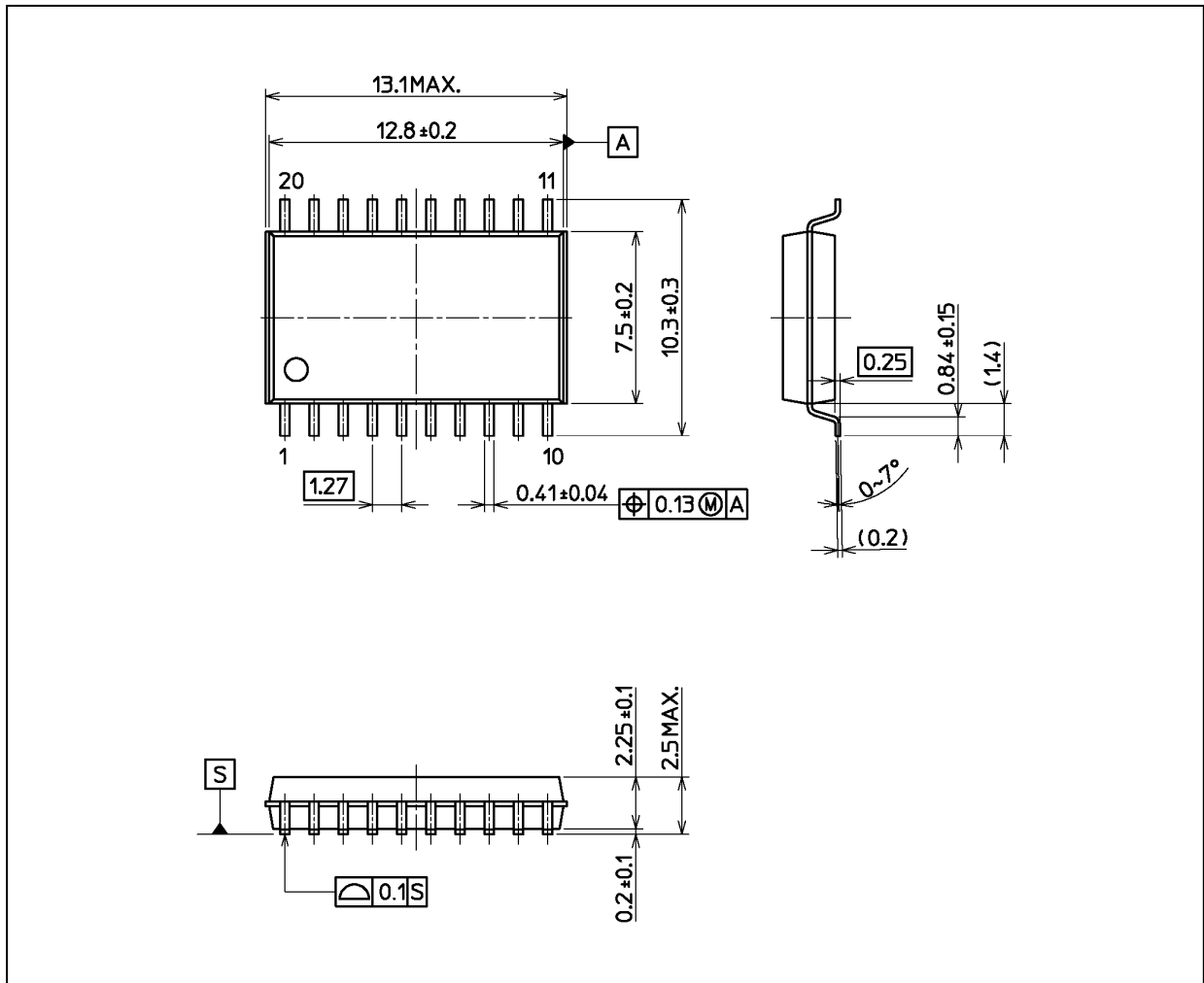
Characteristics	Symbol	Note	Test Condition	$V_{CC}$ (V)	$C_L$ (pF)	Min	Max	Unit
Output transition time	$t_{TLH}, t_{THL}$		—	2.0	50	—	75	ns
				4.5		—	15	
				6.0		—	13	
Propagation delay time (LE-Q)	$t_{PLH}, t_{PHL}$		—	2.0	50	—	155	ns
				4.5		—	31	
				6.0		—	26	
				2.0	150	—	220	ns
				4.5		—	44	
				6.0		—	37	
Propagation delay time (D-Q)	$t_{PLH}, t_{PHL}$		—	2.0	50	—	155	ns
				4.5		—	31	
				6.0		—	26	
				2.0	150	—	220	ns
				4.5		—	44	
				6.0		—	37	
Output enable time	$t_{PZL}, t_{PZH}$		$R_L = 1$ k $\Omega$	2.0	50	—	155	ns
				4.5		—	31	
				6.0		—	26	
				2.0	150	—	220	ns
				4.5		—	44	
				6.0		—	37	
Output disable time	$t_{PLZ}, t_{PHZ}$		$R_L = 1$ k $\Omega$	2.0	50	—	155	ns
				4.5		—	31	
				6.0		—	26	

**12.9. AC Characteristics**  
 (Unless otherwise specified,  $T_a = -40$  to  $125$  °C, Input:  $t_r = t_f = 6$  ns)

Characteristics	Symbol	Note	Test Condition	$V_{CC}$ (V)	$C_L$ (pF)	Min	Max	Unit
Output transition time	$t_{TLH}, t_{THL}$		—	2.0	50	—	90	ns
				4.5		—	18	
				6.0		—	15	
Propagation delay time (LE-Q)	$t_{PLH}, t_{PHL}$		—	2.0	50	—	190	ns
				4.5		—	38	
				6.0		—	32	
				2.0	150	—	265	ns
				4.5		—	53	
				6.0		—	45	
Propagation delay time (D-Q)	$t_{PLH}, t_{PHL}$		—	2.0	50	—	265	ns
				4.5		—	53	
				6.0		—	45	
				2.0	150	—	265	ns
				4.5		—	53	
				6.0		—	45	
Output enable time	$t_{PZL}, t_{PZH}$		$R_L = 1$ k $\Omega$	2.0	50	—	225	ns
				4.5		—	45	
				6.0		—	38	
				2.0	150	—	265	ns
				4.5		—	53	
				6.0		—	45	
Output disable time	$t_{PLZ}, t_{PHZ}$		$R_L = 1$ k $\Omega$	2.0	50	—	225	ns
				4.5		—	45	
				6.0		—	38	

Package Dimensions

Unit: mm



Weight: 0.51 g (typ.)

Package Name(s)
Nickname: SOIC20

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